

L Number	Hits	Search Text	DB	Time stamp
1	1	("20030073295").PN.	USPAT; US-PGPUB	2003/11/12 14:16
2	1	("20030001242").PN.	USPAT; US-PGPUB	2003/11/12 14:26
3	13	(HSG or (hemispheric adj grain adj polysilicon)) and (GeSbTe or chalcogenide or (phase adj change))	USPAT; US-PGPUB	2003/11/12 15:17
4	0	(HSG or (hemispheric adj grain adj polysilicon)) and (GeSbTe or chalcogenide or (phase adj change))	EPO; JPO; DERWENT; IBM_TDB	2003/11/12 15:17
5	0	(HSG or (hemispherical adj grained adj polysilicon)) and (GeSbTe or chalcogenide or (phase adj change))	EPO; JPO; DERWENT; IBM_TDB	2003/11/12 15:17
6	13	(HSG or (hemispherical adj grained adj polysilicon)) and (GeSbTe or chalcogenide or (phase adj change))	USPAT; US-PGPUB	2003/11/12 15:17
7	0	((HSG or (hemispherical adj grained adj polysilicon)) and (GeSbTe or chalcogenide or (phase adj change))) not ((HSG or (hemispheric adj grain adj polysilicon)) and (GeSbTe or chalcogenide or (phase adj change)))	USPAT; US-PGPUB	2003/11/12 15:17
8	24615	(GeSbTe or chalcogenide or (phase adj change))	USPAT; US-PGPUB	2003/11/12 15:23
9	7346	((GeSbTe or chalcogenide or (phase adj change))) and (dielectric or insulative or insulator or insulating)	USPAT; US-PGPUB	2003/11/12 15:24
10	12	((((GeSbTe or chalcogenide or (phase adj change))) and (dielectric or insulative or insulator or insulating)) and HSG	USPAT; US-PGPUB	2003/11/12 15:24
11	0	((((GeSbTe or chalcogenide or (phase adj change))) and (dielectric or insulative or insulator or insulating)) and HSG) not ((HSG or (hemispherical adj grained adj polysilicon)) and (GeSbTe or chalcogenide or (phase adj change)))	USPAT; US-PGPUB	2003/11/12 15:24
12	2161	((((GeSbTe or chalcogenide or (phase adj change))) and (dielectric or insulative or insulator or insulating)) and (bond or bonding)	USPAT; US-PGPUB	2003/11/12 15:25
15	1802	(((((GeSbTe or chalcogenide or (phase adj change))) and (dielectric or insulative or insulator or insulating)) and (bond or bonding)) and @ad<20011231	USPAT; US-PGPUB	2003/11/12 15:27
16	486	(((((GeSbTe or chalcogenide or (phase adj change))) and (dielectric or insulative or insulator or insulating)) and (bond or bonding)) and @ad<20011231) and memory	USPAT; US-PGPUB	2003/11/12 15:34
17	0	(((((GeSbTe or chalcogenide or (phase adj change))) and (dielectric or insulative or insulator or insulating)) and (bond or bonding)) and @ad<20011231) and memory) and hsg	USPAT; US-PGPUB	2003/11/12 15:34
18	0	(((((GeSbTe or chalcogenide or (phase adj change))) and (dielectric or insulative or insulator or insulating)) and (bond or bonding)) and @ad<20011231) and memory) and (hemispherical adj grained)	USPAT; US-PGPUB	2003/11/12 15:35
19	0	(TeGeSb or GeSbTe) and (hemispherical adj grained)	USPAT; US-PGPUB	2003/11/12 15:36
20	1	(phase with change) and (hemispherical adj grained)	USPAT; US-PGPUB	2003/11/12 15:37
21	0	(phase with change) and (hemispherical adj grained)	EPO; JPO; DERWENT; IBM_TDB	2003/11/12 15:53
23	2	(adhesion with (hemispherical adj grained))	EPO; JPO; DERWENT; IBM_TDB	2003/11/12 15:55

24	1	(adhesion with (hemispherical adj grained))	USPAT; US-PGPUB	2003/11/12 15:55
25	3	(adhesion same (hemispherical adj grained))	USPAT; US-PGPUB	2003/11/12 15:56

DERWENT-ACC-NO: 1999-287070

DERWENT-WEEK: 200012

COPYRIGHT 1999 DERWENT INFORMATION LTD

TITLE: Manufacture of a stacked capacitor  
structure for a DRAM  
cell

----- KWIC -----

Basic Abstract Text - ABTX (1):

NOVELTY - A stacked capacitor structure for a DRAM cell  
is manufactured  
using hemispherical grained polysilicon covered by a thin  
heavily doped  
polysilicon layer for improved adhesion and reduced  
capacitor depletion.

IEEE HOME : SEARCH IEEE : SHOP : WEB ACCOUNT : CONTACT IEEE


[Membership](#)
[Publications/Services](#)
[Standards](#)
[Conferences](#)
[Careers/Jobs](#)
**IEEE Xplore**  
Full Text

 Welcome  
 United States Patent and Trademark Office

[Help](#)
[FAQ](#)
[Terms](#)
[IEEE](#)
[Quick Links](#)
[» Search Results](#)
**Welcome to IEEE Xplore**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

 Your search matched **3** of **983558** documents.

 A maximum of **3** results are displayed, **25** to a page, sorted by **Relevance** in **descending** order.

You may refine your search by editing the current search expression or entering a new one in the text box.

**Filter by Contents**

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

 Then click **Search Again**.

hemispheric grain polysilicon

[Search Again](#)
**Search**

- ☐ By Author
- ☐ Basic
- ☐ Advanced

**Results:**

 Journal or Magazine = **JNL** Conference = **CNF** Standard = **STD**
**Member Services**

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

Print Format

[\[Abstract\]](#) [\[PDF Full-Text \(368 KB\)\]](#) **IEEE CNF**
**2 Trends in DRAM dielectrics**
*Tang, K.S.; Lau, W.S.; Samudra, G.S.;*

Circuits and Devices Magazine, IEEE , Volume: 13 Issue: 3 , May 1997

Page(s): 27 -34

[\[Abstract\]](#) [\[PDF Full-Text \(892 KB\)\]](#) **IEEE JNL**
**3 Fabrication and performance of selective HSG storage cells for 256 Mb and 1 Gb DRAM applications**
*Banerjee, A.; Wise, R.L.; Plumton, D.L.; Bevan, M.; Pas, M.F.;*
*Crenshaw, D.L.; Aoyama, S.; Mansoori, M.M.;*

Electron Devices, IEEE Transactions on , Volume: 47 Issue: 3 , March 2000

Page(s): 584 -592

[\[Abstract\]](#) [\[PDF Full-Text \(1088 KB\)\]](#) **IEEE JNL**

IEEE HOME : SEARCH IEEE : SHOP : WEB ACCOUNT : CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

**IEEE Xplore**  
DIGITAL LIBRARYWelcome  
United States Patent and Trademark Office[Help](#) [FAQ](#) [Terms](#) [IEEE](#) [Quick Links](#)[» Search Results](#)**Welcome to IEEE Xplore**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

**Index of Contents**

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

**Search**

- ☐ By Author
- ☐ Basic
- ☐ Advanced

**Member Services**

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

[Print Format](#)Your search matched **[0]** of **[985444]** documents.

You may refine your search by editing the current search expression or entering a new one the text box. Then click search Again.

hsg and gesbte

[Search Again](#)**OR**

Use your browser's back button to return to your original search page.

**Results:****No documents matched your query.**

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#)  
[Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#)  
[No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2003 IEEE — All rights reserved

[IEEE HOME](#) : [SEARCH IEEE](#) : [SHOP](#) : [WEB ACCOUNT](#) : [CONTACT IEEE](#)[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)**IEEE Xplore**  
powered byWelcome  
United States Patent and Trademark Office[Help](#) [FAQ](#) [Terms](#) [IEEE](#) [Quick Links](#)  
[Peer Review](#)[» Search Results](#)**Welcome to IEEE Xplore**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

**Table of Contents**

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

**Search**

- ☐ By Author
- ☐ Basic
- ☐ Advanced

**Member Services**

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

[Print Format](#)Your search matched **[0]** of **[983558]** documents.

You may refine your search by editing the current search expression or entering a new one the text box. Then click search Again.

hsg and chalcogenide

[Search Again](#)**OR**

Use your browser's back button to return to your original search page.

**Results:****No documents matched your query.**

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#)  
[Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#)  
[No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2003 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

**IEEE Xplore**  
DIGITAL LIBRARYWelcome  
United States Patent and Trademark Office[Help](#) [FAQ](#) [Terms](#) [IEEE](#) [Quick Links](#)» [Search Results](#)**Welcome to IEEE Xplore**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

**Types of Content**

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

**Search**

- ☐ By Author
- ☐ Basic
- ☐ Advanced

**Member Services**

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

[Print Format](#)Your search matched **[0]** of **[983558]** documents.

You may refine your search by editing the current search expression or entering a new one the text box. Then click search Again.  
hsg and phase change

[Search Again](#)**OR**

Use your browser's back button to return to your original search page.

**Results:****No documents matched your query.**

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#)  
[Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#)  
[No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2003 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership Publications/Services Standards Conferences Careers/Jobs

**IEEE Xplore**  
DIGITAL LIBRARYWelcome  
United States Patent and Trademark Office[Help](#) [FAQ](#) [Terms](#) [IEEE](#) [Quick Links](#)[» Search Results](#)[Peer Review](#)**Welcome to IEEE Xplore**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

**Tables of Contents**

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

**Search**

- ☐ By Author
- ☐ Basic
- ☐ Advanced

**Member Services**

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

[Print Format](#)Your search matched **[0]** of **[983558]** documents.

You may refine your search by editing the current search expression or entering a new one the text box. Then click search Again.

hemispheric grain polysilicon and phase change

[Search Again](#)**OR**

Use your browser's back button to return to your original search page.

**Results:****No documents matched your query.**

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#)  
[Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#)  
[No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2003 IEEE — All rights reserved

[IEEE HOME](#) : [SEARCH IEEE](#) : [SHOP](#) : [WEB ACCOUNT](#) : [CONTACT IEEE](#)[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)**IEEE Xplore**  
DIGITAL LIBRARYWelcome  
United States Patent and Trademark Office[Help](#) [FAQ](#) [Terms](#) [IEEE](#) [Quick Links](#)  
[Peer Review](#)[» Search Results](#)**Welcome to IEEE Xplore**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

**Index of Contents**

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

**Search**

- ☐ By Author
- ☐ Basic
- ☐ Advanced

**Member Services**

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

[Print Format](#)Your search matched **[0]** of **[985444]** documents.

You may refine your search by editing the current search expression or entering a new one the text box. Then click search Again.

hemispherical grained polysilicon and phase change

[Search Again](#)**OR**

Use your browser's back button to return to your original search page.

**Results:****No documents matched your query.**

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#)  
[Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#)  
[No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2003 IEEE — All rights reserved

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)**IEEE Xplore**  
DIGITAL LIBRARYWelcome  
United States Patent and Trademark Office[Help](#) | [FAQ](#) | [Terms](#) | [IEEE](#) | [Quick Links](#)  
[Peer Review](#)[» Search Results](#)**Welcome to IEEE Xplore**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

**Table of Contents**

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

**Search**

- ☐ By Author
- ☐ Basic
- ☐ Advanced

**Member Services**

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

[Print Format](#)Your search matched **[0]** of **[983558]** documents.

You may refine your search by editing the current search expression or entering a new one the text box. Then click search Again.

hemispherical grained polysilicon and chalcogenide

[Search Again](#)**OR**

Use your browser's back button to return to your original search page.

**Results:****No documents matched your query.**

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#)  
[Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#)  
[No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2003 IEEE — All rights reserved